



NTE2387

MOSFET

N-Channel Enhancement Mode, High Speed Switch

Absolute Maximum Ratings:

Drain–Source Voltage, V_{DS}	800V
Drain–Gate Voltage ($R_{GS} = 20\text{k}\Omega$), V_{DGR}	800V
Gate–Source Voltage, V_{GS}	$\pm 30\text{V}$
Pulsed Drain Current, I_{DM}	16A
Continuous Drain Current, I_D	
$T_C = +25^\circ\text{C}$	4.0A
$T_C = +100^\circ\text{C}$	2.5A
Total Dissipation ($T_C = +25^\circ\text{C}$), P_{tot}	125W
Operating Junction Temperature, T_J	$+150^\circ\text{C}$
Storage Temperature Range, T_{stg}	-55° to $+150^\circ\text{C}$
Maximum Thermal Resistance, Junction-to-Case, R_{thJC}	$1.0^\circ\text{C}/\text{W}$
Typical Thermal Resistance, Junction-to-Ambient, R_{thJA}	$60^\circ\text{C}/\text{W}$

Electrical Characteristics: ($T_C = +25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Static Characteristics						
Drain–Source Breakdown Voltage	$V_{(BR)DSS}$	$I_D = 250\mu\text{A}$, $V_{GS} = 0$	800	—	—	V
Zero–Gate Voltage Drain Current	I_{DSS}	$V_{GS} = 0$, $V_{DS} = 800\text{V}$, $T_C = +25^\circ\text{C}$	—	2	20	μA
		$V_{GS} = 0$, $V_{DS} = 800\text{V}$, $T_C = +125^\circ\text{C}$	—	0.1	1.0	mA
Gate–Body Leakage Current	I_{GSS}	$V_{DS} = 0$, $V_{GS} = \pm 30\text{V}$	—	10	100	nA
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}$, $I_D = 1\text{mA}$	2.1	3.0	4.0	V
Static Drain–Source On Resistance	$R_{DS(\text{on})}$	$V_{GS} = 10\text{V}$, $I_D = 1.5\text{A}$	—	2.7	3.0	Ω
Dynamic Characteristics						
Forward Transconductance	g_{fs}	$V_{DS} = 25\text{V}$, $I_D = 1.5\text{A}$	3.0	4.3	—	mho
Input Capacitance	C_{iss}	$V_{DS} = 25\text{V}$, $V_{GS} = 0$, $f = 1\text{MHz}$	—	1000	1250	pf
Output Capacitance	C_{oss}		—	80	120	pf
Reverse Transfer Capacitance	C_{rss}		—	30	50	pf
Turn–On Time	$t_{d(on)}$	$V_{DD} = 30\text{V}$, $I_D = 2.3\text{A}$, $V_{GS} = 10\text{V}$, $R_{GS} = 50\Omega$, $R_{gen} = 50\Omega$	—	10	25	ns
Rise Time	t_r		—	25	40	ns
Turn–Off Delay Time	$t_{d(off)}$		—	130	150	ns
Fall Time	t_f		—	40	60	ns

Electrical Characteristics (Cont'd): ($T_C = +25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Dynamic Characteristics (Cont'd)						
Internal Drain Inductance	L_D	Measured from contact screw on tab to center of die	-	3.5	-	nH
		Measured from drain lead 6mm from package to center of die	-	4.5	-	nH
Internal Source Inductance	L_S	Measured from the source lead 6mm from package to source bonding pad	-	7.5	-	nH
Source-Drain Diode Ratings and Characteristics						
Continuous Reverse Drain Current	I_{DR}		-	-	4	A
Pulsed Reverse Drain Current	I_{DRM}		-	-	16	A
Diode Forward Voltage	V_{SD}	$I_F = 4\text{A}$, $V_{GS} = 0$	-	1.0	1.3	V
Reverse Recovery Time	t_{rr}	$I_F = 4\text{A}$, $dI_F/dt = 100\text{A}/\mu\text{s}$, $V_{GS} = 0$, $V_R = 100\text{V}$	-	1800	-	ns
Reverse Recovered Charge	Q_{rr}		-	12	-	μC

